

## P3 CF

Finishing process of thin and delicate materials (like ceramics, semiconductor wafers, epoxy mold compound for packaging, etc.) requires accurate thickness measurements not always possible using contact probes. Employing confocal technology, P3CF overcomes such limits by carrying out an indirect measurement of thickness as the difference between the distance of the workpiece and the distance of the reference support
Moreover, since the support is typically a less delicate surface which stands a contact measurement, it is also possible to configure the system for a hybrid measurement combining both contact and optical probes.


| P3CF UNIT | SPECIFICATION |  |
| :---: | :---: | :---: |
| MEASURING FREQUENCY | up to 2.000 Hz |  |
| LIGHT SOURCE | LED |  |
| STANDARD MEASURING MODE | Distance |  |
| RESOLUTION | $0.25 \mu \mathrm{~m}$ |  |
| ANALOG OUT | 2 (0-10Vdc) |  |
| FIELDBUS | Optional |  |
| ENCODER INPUTS | 3 digital (TTL/HTL Differential/Single Ended) |  |
| WEIGHT | 3.5 Kg |  |
| POWER SUPPLY / CONSUMPTION | 24V / 20W |  |
| WORKING TEMPERATURE | $5^{\circ} \mathrm{C}-50^{\circ} \mathrm{C}$ |  |
| PROTECTION RATING | IP40 |  |
| UNIMAR PROBE | Measuring Unit | Values |
| WORKING RANGE | [ $\mu \mathrm{m}$ ] | +/-2000 |
| WEIGHT | [Kg] | 0.45 |
| PROTECTION RATING | IP67 |  |
| CONFOCAL PROBE | Measuring Unit | Values |
| MEASURE RANGE | [ $\mu \mathrm{m}$ ] | 0-2000 |
| WORKING DISTANCE | [ $\mu \mathrm{m}$ ] | 2000 |
| SPOT DIAMETER | [ $\mu \mathrm{m}$ ] | 20 |
| WEIGHT | [Kg] | 1.1 |
| PROTECTION RATING | IP68 |  |

